Imaging Nitrogen in Individual Carbon Nanotubes

Jigang Zhou,*† Jian Wang,*† Hao Liu,† Mohammad N. Banis,† Xueliang Sun,† and Tsun-Kong Sham*‡

†Canadian Light Source Inc., Saskatoon, Canada, ‡Department of Mechanic and Materials Engineering, and §Department of Chemistry, The University of Western Ontario, London, Canada

**ABSTRACT**

Semiquantitative chemical imaging of the spatial distribution of nitrogen in a carbon matrix, adsorbed/intercalated \( \text{N}_2 \), and highly concentrated \( \text{N}_2 \) in nitrogen-doped carbon nanotubes (N-CNTs) with a spatial resolution of 30 nm has been obtained by scanning transmission X-ray microscopy (STXM). The local electronic structures of individual N-CNTs at C and N K-edges have been extracted from STXM image stacks (sensitive to bulk) and compared with that of N-CNT using X-ray absorption near-edge structure spectroscopy in total electron yield mode (sensitive to surface). The polarization-dependent STXM measurement has revealed the preferred orientation of \( \text{N}_2 \), parallel to the N-CNT long axis.

**SECTION**

Nanoparticles and Nanostructures

Nitrogen-doped carbon nanotubes (N-CNTs) have shown great promise in gas storage, energy conversion and storage, and electronics applications.1–6 Moreover, first-principle simulations7,8 have suggested that polymeric nitrogen (single-bonded nitrogen)9 can be stabilized in carbon nanotubes, forming nanoscale energetic materials. It has been assumed that doping N in CNTs can produce such nanoelectronic materials. Nitrogen in N-CNTs exhibits a very broad range of structures such as graphitic-like, pyridine-like, pyrrolic, cross-linked sp\(^3\) structure, and gaseous \( \text{N}_2 \).10–13 Different nitrogen sites play different roles in tailoring the structure of a N-CNT and hence its performance. Understanding and controlling the chemistry and electronic structure in N-CNTs is of foremost importance in achieving its promise in broad practical applications. To this end, being able to image the local chemistry and electronic structure variations within a single carbon nanotube is critical, but such information was apparently absent until now.2–4,6 Considerable efforts have been made to identify the nitrogen chemistry in N-CNTs by electron energy loss spectroscopy (EELS),1 X-ray photoelectron spectroscopy (XPS), and X-ray absorption near-edge structure (XANES) spectroscopy.10,12–14 Radiation damage1 and energy resolution limit the application of EELS, although it has high spatial resolution. In contrast, XANES spectroscopy is element-specific with high energy resolution and is sensitive to the local chemistry of the absorbing atom. It is also less susceptible to radiation damage. Although the electronic structures of N-CNTs have been investigated by XANES10,12–14 studies, they only provide averaged information for a large sampling area.2 Due to the difference in helicity, defects, and diameter, a bundle of N-CNTs inevitably has a much broader variation in electronic structure. Such variations can only be addressed by the spectromicroscopic study of an individual N-CNT. With the advent of the brilliant and polarization-controlled third-generation synchrotron sources, the state-of-the-art spectromicroscopic technique, scanning transmission X-ray microscopy (STXM), provides an excellent combination of high spatial (30 nm) and energy resolution (resolving power up to 10000) as well as variable polarizations (linear to circular and elliptical) for chemical speciation. STXM has been successfully applied to the studies of the electronic structure and surface defects of individual CNTs15–17 and a single catalyst under relevant operation conditions18,19 and the chemical imaging of \( \text{RuO}_2 \) supported on carbon nanotubes.20 This work reports an application of STXM to obtain the chemical imaging and the electronic structure of individual N-CNTs in considerably greater details than ever before. Specifically, the XANES of the N K-edge was used to image various N sites, the substituted N, adsorbed/intercalated \( \text{N}_2 \), and gaseous \( \text{N}_2 \) trapped in the cavity of a single N-CNT. Furthermore, the nitrogen and carbon chemistry on different locations of the N-CNT was studied by XANES at the N and C K-edges. High-resolution spectroscopy clearly shows the fine signatures of the vibronic N 1s → \( \pi^* \) transitions in molecular nitrogen encapsulated inside of the tube. Finally, the parallel orientation of \( \text{N}_2 \) in the N-CNT was revealed by polarized STXM.

N K-edge STXM image stacks of individual N-CNTs were fitted with two reference spectra, the N K-edge XANES of the N-CNTs (representing the substituted N, displayed in Figure 1d) and molecular \( \text{N}_2 \). Note that we observe \( \text{N}_2 \) molecules trapped inside of the N-CNT, and they are henceforth denoted condensed \( \text{N}_2 \), although part of them are most likely pressurized \( \text{N}_2 \) (see below). The chemical maps thus obtained are shown in Figure 1a (condensed \( \text{N}_2 \)) and b (substituted N in a carbon matrix). It is obvious from the mapping in Figure 1a that the \( \text{N}_2 \) thickness varies among N-CNTs and even along individual

Received Date: March 22, 2010
Accepted Date: May 10, 2010
Published on Web Date: May 17, 2010
N-CNTs. A thin layer of \( \text{N}_2 \) (less than 5 nm of condensed \( \text{N}_2 \)) is widely and evenly distributed over the N-CNTs, which is considered to be the adsorbed/intercalated \( \text{N}_2 \) located within and on the inner surface of the tube wall. More highly concentrated \( \text{N}_2 \) (about 20–45 nm of condensed \( \text{N}_2 \)) is distributed in some isolated regions, suggesting that molecular \( \text{N}_2 \) is trapped inside of the tube compartments. Such high-concentration \( \text{N}_2 \) (equivalent to 15–40 nm of condensed \( \text{N}_2 \) after removing the contribution from adsorbed/intercalated \( \text{N}_2 \) in the wall) sealed in CNTs with an inner diameter of about 100 nm indicates a very high pressure (estimated to be \( \sim \)50 atm by scaling to the absorbance of gaseous \( \text{N}_2 \) with a known pressure).

The molecular nature of the high-concentration \( \text{N}_2 \) is revealed by the high energy resolution vibronic structures of the \( \text{N} 1\text{s} \rightarrow \pi^* \) transitions, as shown in Figure 1e. The distribution of highly concentrated \( \text{N}_2 \) among N-CNTs highlights their structural variation. From Figure 1b, a quantitative map of substituted N in N-CNTs, a number of interesting observations are apparent. First, substituted N occurs more evenly along the N-CNT. Second, the compartment membranes in the bamboo-like structure (which has been observed by transmission electron microscopy in Supporting Information Figure S4) are well-resolved just like that of the tubular structure, which means that substituted N also presents in the compartment membranes. Finally, the doping of nitrogen inside of the carbon nanotube is about 1–2 nm across the tube wall. The color composite map of \( \text{N}_2 \) and substituted N in the individual N-CNTs is displayed in Figure 1c.

In addition to chemical mapping, STXM probes the electronic structure locally (e.g., in a single pixel), that is, nanospectroscopy. Figure 1d compares the N K-edge transmission XANES of the wall and the center regions of a N-CNT (\( \text{N}_2 \)-rich regions) along with N K-edge XANES of N-CNTs recorded in TEY mode; (e) high-resolution N K-edge XANES spectra of \( \text{N}_2 \) gas and \( \text{N}_2 \) in N-CNTs obtained by STXM point spectrum (single pixel) scans. The peak width is labeled along with each peak. The fit for the first four peaks are at least semiquantitative. (f) C K-edge XANES of the wall of a N-CNT and a native CNT.
orbital s containing N 2p character. This is undoubtedly direct evidence of successful nitrogen doping into the carbon matrix, forming unsaturated C=N bonds in N-CNTs. Three π* peaks at 599, 401, and 402.6 eV are attributed to the pyridine-like (though this peak could also be the cyanide-like structure, but this does not agree with our XPS results 21,22) and graphite-like N or N 2 and oxidized pyridine-like bonding in nitrogenated carbon materials. 11–13,21 The high-resolution vibrational structure of a highly concentrated N 2 region (Figure 1e) presents the high energy resolution feature in STXM which was not observed in EELS. Similar vibrational fine structure in N 2 molecular clusters has been reported. 23 The broadening of the first four vibrational features in N 2 sealed in a N-CNT relative to that of gaseous N 2 supports the high N 2 pressure in N-CNTs. The effect of N substitution on N-CNTs was also studied by C K-edge XANES extracted from C K-edge STXM stacks. The XANES at the N-CNT wall was compared to the C K-edge XANES from a native CNT, as shown in Figure 1f. The π* transition at 285.1 eV and σ* at 291.5 and 292.5 eV are characteristic of the graphite structure. In between those transitions, a relatively broad peak at 288.3 eV appears in the XANES of the CNT, which indicates the existence of a carboxylic group. 21 In contrast, a rather sharp transition peak at 287.5 eV is displayed in XANES from the wall of the N-CNT. This spectroscopic signature should be due to the pyridine-like N substitution in a carbon matrix. The π* transition in the N-CNT also shifts slightly to lower energy. The shift is accompanied by a reduction in intensity. All of these observations indicate electron doping by the substituted N.

Furthermore, polarized STXM 17 was applied to study the orientation of nitrogen in N-CNTs. It was performed by applying the linear inclined polarization parallel (+30°) and perpendicular (−60°) to the selected N-CNT’s long axis (see Figure 2 and Supporting Information Figure S3). Then, well-focused individual images were taken at selected energies for each polarization. The polarization dependence was evaluated based on the normalized intensity ratio of I/E∥/I/E⊥ for the π* feature. The polarization maps of N-CNT and N 2 at the C and N π*, respectively, were generated by subtracting images with the beam E vector (−60°) perpendicular to the tube by images with the beam E vector (+30°) parallel to the tube. (The detailed polarization experiment and analysis are described in the Supporting Information). Figure 2a and b display the distribution of polarized N 2 and N-CNTs, respectively. A color composite polarization map (Figure 2c) of N 2 (in red) and N-CNT (in blue) was made to guide the visualization of the polarization effect. It clearly shows a strong correlation of the polarized N 2 related to the N-CNT tube wall. Such a polarization effect suggests that polarized N 2 aligns along the tube’s long axis as carbon in N-CNT does. The low polarization dependence of N 2 (0.86, Supporting Information Table S1) correlates with the low polarization dependence of the N-CNT at the carbon K-edge (0.79, Supporting Information Table S1) (a native CNT with a polarization dependence of 0.3, 17 the low polarization at the C K-edge in the N-CNT is due to its intrinsic low crystallinity. 22). This correlation hints that the molecular axis of the adsorbed and intercalated N 2 is oriented with respect to the wall of the N-CNT as a template.

In summary, we have reported the chemical mapping of different N components of individual N-CNTs obtained by STXM with a spatial resolution of 30 nm. We have identified substitutional N, N 2 adsorbed and intercalated between graphene walls, and molecular N 2 trapped in bamboo-like compartments. XANES spectra at the N K-edge and C K-edge of individual N-CNTs have been used to reveal the electronic structure variation within individual N-CNTs and among N-CNTs. Furthermore, the polarized STXM confirms the presence of sporadic regions of polarized N 2 near the CNT walls, which might be relevant to a parallel orientation of adsorbed and intercalated N 2 to the tube’s long axis.

METHODS

Nitrogen-doped carbon nanotube arrays (N-CNTs) were prepared by the floating catalyst chemical vapor deposition method. The details of preparation can be found elsewhere. 22 Briefly, 100 mg of ferrocene was used as the precursor to produce metallic iron and melamine as the nitrogen source in making N-CNTs on a Si wafer. The N-CNTs thus obtained have been characterized to contain 8% nitrogen using XPS. 22 The morphology of the N-CNT was studied by transmission electron microscopy (TEM) imaging using a Philips CM10 TEM microscope operating at 80 KeV. To perform STXM, the N-CNT sample was scratched from the Si substrate and predispersed in methanol and then deposited on SiN x wafers (thickness 75 nm, Norcada Inc.) using a micropipet. The STXM was
performed on the SM beamline at the Canadian Light Source (CLS), a 2.9 GeV third-generation synchrotron source. The beamline is equipped with an APPLE II type elliptically polarizing undulator (EPU), which provides circularly polarized light (up to 1000 eV) and linearly polarized light (150–2500 eV) with polarization adjustable from +90 to −90°. The STXM principle and the design of the microscope have been described elsewhere. In short, the monochromatic X-ray beam is focused by a Fresnel zone plate to a 30 nm spot (this work) on the sample. The sample is raster-scanned with synchronized detection of transmitted X-rays to generate images. Chemical imaging and XANES spectra are obtained using image sequence (stack) scans over a range of photon energies at a specific element edge. The X-ray photon energy scale was calibrated by a gas-phase XANES of photon energies at a specific element edge. The X-ray (1) Terrones, M.; Kamalakaran, R.; Seeger, T.; Ruhle, M. Novel Nanoscale Gas Containers: Encapsulation of N2 in CN Nanotubes. Chem. Commun. 2000, 2335–2336.

This material is available free of charge via the Internet at http://pubs.acs.org.

AUTHOR INFORMATION

Corresponding Author:

*To whom correspondence should be addressed. E-mail: jiangzhou@lightsource.ca (J.Z.), jian.wang@lightsource.ca (J.W.), tsham@uwo.ca (T.-K.S.).

ACKNOWLEDGMENT We thank Dr. C. Karunakaran and Y. Lu of the Canadian Light Source for their technical assistance on the SM beamline and T. Regeir on the SGM beamline. Research at CLS is supported by NSERC, OIT, CFI, and CRC (T.-K.S. and X.S.).

REFERENCES


